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Seet 1 of 1	Attorney Docket Number	O65781		

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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS					
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Examiner Signature	5.01.1	Our	Date Considered	5/	29/	07
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<sup>\*</sup>FXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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